



# Deutsches IT-Sicherheitszertifikat

erteilt vom



Bundesamt für Sicherheit in der Informationstechnik

**BSI-DSZ-CC-S-0169-2021**

Security IC Wafer Testing



**nepes Ochang 2nd factory, 587-32, Gwahaksaneop 2-ro, Ochang-eup, Cheongwon-gu, Cheongju-si, Chungcheongbuk-do, Republic of Korea**

of nepes Ark Corporation

Life cycle phase: Phase 3, Wafer Testing as part of IC Manufacturing

Assurance (\*): Common Criteria Part 3 conformant  
- ALC\_CMC.5, ALC\_CMS.5, ALC\_DVS.2,  
ALC\_LCD.1  
- ALC\_DEL.1, ALC\_TAT.3

valid until: 16 May 2023

The site identified in this certificate has been evaluated by an approved evaluation facility using the Common Methodology for IT Security Evaluation (CEM), Version 3.1 extended by BSI Scheme procedures including the Supporting Document Guidance CCDB-2007-11-001 for conformance to the Common Criteria for IT Security Evaluation (CC), Version 3.1.

This certificate applies only to the specific site as indicated above and in conjunction with the complete content of the Certification Report and the Site Security Target.

(\*) For information on the evaluated scope of the certified site and the application of the assurance components listed above and their relevance and applicability for the certified site see Certification Report.

The evaluation has been conducted in accordance with the provisions of the certification scheme of the German Federal Office for Information Security (BSI) and the conclusions of the evaluation facility in the evaluation technical report are consistent with the evidence adduced.

This certificate is not an endorsement of the site by the Federal Office for Information Security or any other organisation that recognises or gives effect to this certificate, and no warranty of the site by the Federal Office for Information Security or any other organisation that recognises or gives effect to this certificate, is either expressed or implied.

Bonn, 17 May 2021

For the Federal Office for Information Security

*Sandro Amendola*

Sandro Amendola  
Head of Division

